Attention for Inference Compilation

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Abstract: We present a neural network architecture for automatic amortized inference in universal probabilistic programs which improves on the performance of current architectures. Our approach extends inference compilation (IC), a technique which uses deep neural networks to approximate a posterior distribution over latent variables in a probabilistic program. A challenge with existing IC network architectures is that they can fail to capture long-range dependencies between latent variables. To address this, we introduce an attention mechanism that attends to the most salient variables previously sampled in the execution of a probabilistic program. We demonstrate that the addition of attention allows the proposal distributions to better match the true posterior, enhancing inference about latent variables in simulators.

1 INTRODUCTION

Probabilistic programming languages (van de Meent et al., 2018; Mansinghka et al., 2014; Milch et al., 2005; Wood et al., 2014; Minka et al., 2008; Goodman et al., 2008; Bingham et al., 2018; Tran et al., 2016) allow for automatic inference about random variables in generative models written as programs. Conditions on these random variables are imposed through observe statements, while the sample statements define latent variables we seek to draw inference about. Common to the different languages is the existence of an inference backend, which implements one or more general inference methods.

Recent research has addressed the task of making repeated inference less computationally expensive, by using up-front computation to reduce the cost of later executions, an approach known as amortized inference (Gershman and Goodman, 2014). One method called inference compilation (IC) (Le et al., 2017) enables fast inference on arbitrarily complex and non-differentiable generative models. The approximate posterior distribution it learns can be combined with importance sampling at inference time, so that inference is asymptotically correct. It has been successfully used for Captcha solving (Le et al., 2017), inference in particle physics simulators (Baydin et al., 2019), and inference in heat-transfer finite element analysis simulators (Munk et al., 2019).

The neural network used in IC is trained to approximate the joint posterior given the observed variables by sequentially proposing a distribution for each latent variable generated during an execution of a program. As such, capturing the possible dependencies on previously sampled variables is essential to achieving good performance. IC uses a Long Short Term Memory (LSTM)-based architecture (Hochreiter and Schmidhuber, 1997) to encapsulate these dependencies. However, this architecture fails to learn the dependency between highly dependent random variables when they are sampled far apart (with several other variables sampled in-between). This motivates allowing the neural network which parameterizes the proposal distribution for each latent variable to explicitly access any previously sampled variable. Inspired by the promising results of attention for tasks involving long-range dependencies (Jaderberg et al., 2015; Vaswani et al., 2017; Seo et al., 2016), we implemented an attention mechanism over previously sampled values. This enables the network to selectively attend to any combination of previously sampled values, regardless of their order and the trace length. We show that our approach significantly improves the approximation of the posterior, and hence facilitates faster inference.
2 BACKGROUND

2.1 Probabilistic Programming

Probabilistic programming languages (PPLs) allow the specification of probabilistic generative models (and therefore probability distributions) as computer programs. Universal PPLs, which are based on Turing complete languages, may express models with an unbounded number of random variables. To this end, they combine traditional programming languages with the ability to sample a latent random variable (using syntax which we denote as a sample statement) and to condition these latent variables on the values of other, observed, random variables (using an observe statement). More formally, following (Le et al., 2017), we will operate on higher-order probabilistic programs in which we discuss the joint distribution of variables in an execution “trace” \((x_t, a_t, i_t)\), where \(t = 1, \ldots, T\), with \(T\) being the trace length (which may vary between executions). \(x_t\) denotes the value sampled at the \(r\)th sample statement encountered, \(a_t\) is the address of this sample statement and \(i_t\) represents the instance count: the number of times the same address has been encountered previously, i.e., \(i_t = \sum_{j=1}^{t} 1(a_t = a_j)\). We shall assume that there is a fixed number of observations, \(N\), and these are denoted by \(y = (y_1, \ldots, y_N)\), and we denote the latent variables as \(x = (x_1, \ldots, x_T)\). Using this formalism, we express the joint distribution of a trace and observations as,

\[
p(x, y) = \prod_{i=1}^{T} f_{a_i}(x_i | x_{i-1}) \prod_{n=1}^{N} g_{a_n}(y_n | x_{1:n(a_n)}),
\]

where \(f_{a_i}\) is the probability distribution specified by the sample statement at address \(a_i\), and \(g_{a_n}\) is the probability distribution specified by the \(n\)th observe statement. \(\tau\) denotes a mapping from the index, \(n\), of the observe statement to the index of the most recent sample statement before the \(n\)th observe statement.

As an example, consider the simple circuit shown in Figure 2, which expresses the joint distribution over the battery voltage, \(V\), whether the resistor is faulty, \(F\), the resistance of the resistor, \(R\), and the measured current, \(I\), as \(p(V, F, R, I) = p(\bar{V}|V, R)p(R|F)p(F)p(V)\).

Traces will have the form \((x_t, a_t, i_t)_{t=1}^{3}\) where there are two trace “types,” one corresponding to the sequence of addresses of random variables generated if the resistor is faulty, and the other the opposite. In other words \(a_1\) is the address where \(V\) is sampled, \(a_2\) is the address where \(F\) is sampled, and \(a_3\) is the address from which \(R\) is sampled, which depends on \(F\). The instance counts in this program are always \(i_1 = i_2 = i_1 = 1\), and the observation, measured_current \(\sim N(1, 0.001)\), with \(N = 1\).

This generative model allows posterior inference to be performed over the joint distribution of the input voltage \(V\), current \(I\), and “faulty” variable \(F\) given the observed measured_current. Estimates of the marginal posterior distribution over \(F\) make it possible to directly answer questions such as whether the resistor is faulty or not. We will return to a more complex version of this problem in Section 4.3.

Generally, PPLs are designed to infer posterior distributions over the latent variables given the observations. Inference in probabilistic programs is carried out with algorithms such as Sequential Importance Sampling (SIS) (Arulampalam et al., 2002), Lightweight Metropolis-Hastings (Wingate et al., 2011), and Sequential Monte Carlo (Del Moral et al., 2006). However, these algorithms are too computationally expensive for use in real-time applications. Therefore, recent research (Le et al., 2017; Kulkarni et al., 2015) has considered amortizing the computational cost by performing up-front computation (for a given model) to allow faster inference later (given this model and any observed values).

2.2 Inference Compilation

Inference compilation, or IC (Le et al., 2017), is a method for performing amortized inference in the framework of universal probabilistic programming. IC involves training neural networks, which we describe as “inference networks,” whose outputs parameterize proposal distributions used for Sequential Importance Sampling (SIS) (Arulampalam et al., 2002). IC attempts to match the proposal distribution, \(q(x|y; \phi) = \prod_{i=1}^{N} g_{a_i}(x_i | x_{1:i-1}, y)\), close to the true posterior, \(p(x|y)\) using the Kullback-Leibler divergence, \(KL(p(x|y)||q(x|y; \phi))\), as a measure of “closeness”. In order to ensure closeness for any observed \(y\), an expectation of this divergence is taken with respect to \(p(y)\),

\[
L(\phi) = \mathbb{E}_{p(y)}[KL(p(x|y)||q(x|y; \phi))] = \mathbb{E}_{p(x|y)}[- \log q(x|y, \phi)] + \text{const.}
\]

(2)

The parameters, \(\phi\), are updated by gradient descent with the following gradient estimate of (2),

\[
\nabla_{\phi} L(\phi) \approx \frac{1}{M} \sum_{m=1}^{M} -\nabla_{\phi} \log q(x_m|y_m, \phi),
\]

(3)

where \((x_m, y_m) \sim p(x, y)\) for \(m = 1, \ldots, M\). Note that the loss used, and the estimates of the gradients, are identical to those in the sleep-phase of wake-sleep (Hinton et al., 1995).

The architecture used in IC (Baydin et al., 2019; Le et al., 2017) consists of the black components
Figure 1: Feedforward and LSTM neural network architectures with attention mechanisms. The components inside the dashed line are run once at each sample statement in a program trace, while the parts outside this line are run only once per trace. The added attention mechanism is shown in blue.

shown in Figure 1b. Before performing inference, observations $y$ are embedded by a learned observe embedder, $f_{obs}$. At each sample statement encountered as the program runs, the correspondingly LSTM runs for one time step. It receives an input consisting of the concatenation of the embedding of the observed values, $f_{obs}(y)$, an embedding of $x_{t-1}$, the value sampled at the previous sample statement, embeddings of the current and previous address, instance and distribution-type. The embedder used for $x_{t-1}$ is specific to $(a_{t-1}, i_{t-1})$, the address and instance from which $x_{t-1}$ was sampled. The output of the LSTM is fed into a proposal layer, which is specific to the address and instance $(a_t$ and $i_t)$. The proposal layer outputs the parameters, $\eta_t$, of a proposal distribution for the variable at this sample statement.

2.3 Dot-product Attention

Attention has proven useful in a number of tasks, including image captioning, machine translation, and image generation (Xu et al., 2015; Bahdanau et al., 2014; Gregor et al., 2015). The two broad types of attention are hard and soft attention. Hard attention (Ba et al., 2014; Xu et al., 2015) selects a single “location” to attend to, and thus requires only this location to be embedded. However, it is non-differentiable. In contrast, soft attention mechanisms (Vaswani et al., 2017; Xu et al., 2015) are fully differentiable and here we focus especially on dot-product attention (Luong et al., 2015; Vaswani et al., 2017).

The dot-product attention module (Luong et al., 2015; Vaswani et al., 2017), shown in Figure 5, receives three inputs: one or more query vectors (which describe the desired properties of the locations to attend to), a key vector for each location, and a value vector for each location; these are represented as the matrices $Q \in \mathbb{R}^{q \times k}$, $K \in \mathbb{R}^{k \times l}$, and $V \in \mathbb{R}^{l \times v}$ respectively. Note that in our context a location corresponds to a previously sampled value. Here, $l$ is the number of locations, $k$ is the length of each query and key embedding, $v$ is the length of each value embedding, and $q$ is the number of queries. For each query, attention

```
def circuit(measured.current):
    V = sample(Normal(mean=5, std=0.01))
    F = sample(Bernoulli(0.1))  # faulty or not
    if F:
        R = sample(Uniform(low=0, high=10))
    else:
        R = sample(Normal(mean=5, std=0.1))
    I = V/R  # simulate circuit
    observe(measured.current, likelihood=Normal(mean=I, std=0.001))
    return R
```

Figure 3: Probabilistic program modeling the circuit in Figure 2 with a possibly faulty resistor. First the voltage, $V$, of the battery is sampled from a Gaussian prior centered on $5V$. We then sample whether or not the resistor is faulty. If it is, its value is sampled from a broad uniform distribution. Otherwise, its value is sampled from a tightly peaked Gaussian. A noisy measurement of the current is then sampled from a Gaussian prior centered on the true value.
weights are computed for every location by taking the dot-product of the query vector and the relevant key.

3 METHOD

We augment both the LSTM and feedforward architectures with dot-product attention over all previously sampled variables, as shown in Figure 1. Although soft attention is, in many cases, vastly more computationally expensive than hard attention, this is not the case for our application; since the embedding of each sampled value can be used at every later time step, the cost of calculating these embeddings scales only linearly with trace length. This is no worse than the rate that hard attention achieves. We therefore use soft attention for the ease of training.

During training we build a data structure, $d_{k,v,q}$, with associative mappings linking address/instance pairs $(a,i)$ to key, value and query embedders. The embedders in $d_{k,v,q}$ are constructed dynamically for each new address and instance pair $(a_i, i)$. During inference, the queries, keys, and values fed to the attention mechanism at each sample statement are calculated as follows: for the first sample statement, identified by $(a_1, i_1)$, no previously sampled variables exist and so the attention module outputs a vector of zeros. Using the associated key and value embedders in $d_{k,v,q}$, the variable sampled, $x_i$, is embedded to yield a key and a value, $k_i$ and $v_i$. $(k_i,v_i)$ are kept in memory throughout the trace, allowing fast access for subsequent sample statements. The second sample statement can attend to the first sampled variable via $(k_1,v_1)$ using a query. The embedder used for finding the query takes as input the observe embedding, $f^{obs}(y)$, and is specific to the current address and instance $(a_2, i_2)$. As with the key/value embedders, the query embedder is found in $d_{k,v,q}$. The output of the attention module is then fed to the LSTM or proposal layer (see Figure 1). As for $x_1, x_2$ are sampled and embedded using the embedders stored in $d_{k,v,q}$, yielding the key, value pair $(k_2, v_2)$. This procedure is repeated until the end of the trace, as defined by the probabilistic program. In the context of higher-order programs, an address and instance pair may be encountered during inference that has not been seen during training. In this case the proposal layers have not been trained, and so the standard IC approach is to use the prior as a proposal distribution. For the same reason, the key/value embedders do not exist and so no keys or values are created for this $(a_i, i_i)$. This prevents later sample statements from attending to the variable sampled at $(a_i, i_i)$.

4 EXPERIMENTS

We consider feedforward and LSTM architectures both with and without attention, which we denote FF w/o ATT, FF w/ ATT, LSTM w/o ATT and LSTM w/ ATT. We compare them through experiments with inference in three probabilistic programs: a pedagogical example to illustrate a failure case of the LSTM architecture; a model of gene expression as defined by the probabilistic program. In the context of higher-order programs, an address and instance pair may be encountered during inference that has not been seen during training. In this case the proposal layers have not been trained, and so the standard IC approach is to use the prior as a proposal distribution. For the same reason, the key/value embedders do not exist and so no keys or values are created for this $(a_i, i_i)$. This prevents later sample statements from attending to the variable sampled at $(a_i, i_i)$.
Figure 6: Fifth-order band-pass Butterworth filter with resistors, capacitors and inductors denoted by $R$, $C$, and $L$ respectively. The dashed lines represent possible short circuits. The existence of these short circuits and whether or not each component is faulty (represented by a noisy component value) or disconnected is sampled according to the generative model. Given observations of $V_{out}$ for various input frequencies, the task is to infer a distribution over possible faults such as short circuits and poorly connected or incorrectly valued components.

Figure 7: Reconstruction of the output voltage using samples from each proposal distribution. In the architectures with attention, the sampled voltages are almost all close to the observations (green ‘x’s) whereas, without attention, the proposals place high probability in regions which do not fit the observations. These better proposal distributions lead the higher effective sample sizes shown in each figure (mean and standard deviation, calculated with 5 estimates). The proposal distribution is shown using 100 samples from each architecture.

Figure 8: A visualisation of the proposal distributions given some observation sampled from the model. The pie charts show the probability of different possibilities: that there are no faults, multiple faults, or one of multiple specific types of fault. For each architecture, 1000 unweighted samples are shown. A ‘ground truth’ posterior, created with 10000 importance-weighted samples from LSTM w/o ATT, is shown to the right. Since it is probable that exactly one of the faults ‘C2 short’ or ‘C4 short’ has occurred, there is a dependence between these two variables. Either an LSTM or an attention mechanism (or both) can be seen to be sufficient to capture this dependence (thus reducing the error of the weighted posterior approximation). The error is calculated by embedding the samples as a vector where each element corresponds to a possible fault and is 1 if this fault is present, or 0 otherwise. The L2-Wasserstein distance from the ground truth is then measured.

size (64) and learning rate ($10^{-3}$). The only exception to this is that a learning rate of $10^{-4}$ was used to stabilise training of the gene expression model.

### 4.1 Magnitude of Random Vector

Our first program samples two latent variables, $x$ and $y$, from identical and independent normal distributions, $N(0, \sigma_p)$. An observation of $x^2 + y^2$ is then made with Gaussian noise, and denoted $\tilde{r}^2 \sim N(\tilde{r}^2|x^2 + y^2, \sigma_t)$. We wish to infer the posterior over $x$ and $y$ conditioned on this. We use $\sigma_p = 10$ and $\sigma_t = 0.5$, giving a peaked posterior exhibiting circular symmetry, and so a strong dependence between $x$ and $y$. To test the inference network’s ability to capture long-term dependencies, we sample “nuisance” variables between sampling $x$ and $y$. These are not used elsewhere in the program, serving only to increase the “distance” between $x$ and $y$. We provide pseudocode for this program in the appendix.

All inference networks for this model are trained for 2000000 traces. Figure 4 shows samples of $x$ and $y$ from learned proposal distributions for two programs with different numbers of nuisance variables (which are marginalized out). The inference network with an attention mechanism can be seen to learn the dependency even with 50 nuisance variables, while the LSTM cannot.
4.2 Plant Gene Expression

We consider a model of gene expression for Arabidopsis thaliana, a small plant. This was presented by (Opgen-Rhein and Strimmer, 2007) as a Bayesian network, and we write it as a probabilistic program. Although this model has simple link functions (each node is normally distributed with mean given by an affine function of the values of parent nodes), it tests the ability of each architecture to learn a dependency structure from a real-world simulator. The network contains 107 nodes and 150 edges. We randomly select 40 of the 67 leaf nodes to be observable, and attempt to infer the values of all other nodes given these. We train inference networks for 4000000 traces for this model. Visualizations of the attention weights for this model and the magnitude model are in the appendix.

4.3 Electronic Circuit Fault Diagnosis

The final probabilistic program we consider is a model of an electronic circuit (specifically, a bandpass Butterworth filter). The model samples many random variables describing the components values and the existence of possible faults (such as short-circuits or missing components). A pre-existing circuit simulator (Venturini et al., 2017) then generates the complex-valued output voltage (i.e. voltage magnitude and phase) at 40 different input frequencies. Given an observation of this (under Gaussian noise), we infer what faults, if any, exist. An illustration of the Butterworth filter can be found in Fig. 6. The inference networks are trained for 3000000 traces.

To perform inference we write a probabilistic program (see appendix) that iterates through each component of the circuit and samples in the following order: first, whether or not it is correctly connected to the rest of the circuit. Second, the component value is sampled from a mixture of a broad uniform distribution and a tightly peaked Gaussian, both centered on the nominal value. The value is sampled from the tightly peaked Gaussian with 98% probability and from the uniform distribution with 2% probability. Conceptually, one can interpret the tightly peaked Gaussian as the distribution given that the component has been correctly made. The broad uniform distribution represents the distribution for components that are faulty.

To test each inference network, we generate 100 different observations by running the probabilistic program, and attempt to infer the posterior using each different network architecture. For each inference network architecture, we estimate the posterior distribution 5 times using importance sampling with 20 traces each time. Across the 5 estimates, we compute the average ESS, and average these over all 100 observations. The averaged results were 1.40 for FF w/o ATT, 7.26 for LSTM w/o ATT, 8.46 for FF w/ ATT and 8.35 for LSTM w/ ATT. The attention-based architecture has an 16.5% higher average ESS than the LSTM core, showing that the use of attention leads to quantitatively better proposal distributions.

We further find that whenever the observed signal appears to originate from a correctly working Butterworth filter, all architectures seem to produce reasonable predictive posterior distributions - i.e. the distribution of the voltage signal generated by the sampled latent variables. However, the attention-based architectures yield a higher average ESS with only a few exceptions. When the observed signal clearly originates from an erroneous filter, MFF w/o ATT produces predictive posterior distributions which poorly fit the observed data. The LSTM-based architecture produces better predictive posterior distributions but these are still significantly worse than the distributions produced by the attention-based architecture in almost all cases where the filter is broken.

Figure 7 shows inference performance for one such observation originating from a filter in which the component is faulty. We plot voltages generated according to the sampled latent variables from the predictive proposal distributions using each architecture. The proposals from FF w/ ATT and LSTM w/ ATT are clustered near to the observations, whereas FF w/o ATT and LSTM w/o ATT produce many proposals that do not fit the observations.

We suspect that these outliers occur due to the inability of MFF w/o ATT and M1,STM w/o ATT to learn long-range dependencies. For example, an output voltage of zero could be explained by a number of different faults (e.g. a short-circuit across $C_2$ or across $C_4$). If the resulting dependency between these can be learned, the proposals could consistently predict that only one is broken (predicting more would be unlikely due to the strong prior on parts working). However, if the dependency is not captured, the proposals would be prone to predicting that zero or multiple components are broken. This interpretation is supported by Figure 7, where both architectures without attention are seen to sometimes propose an output voltage corresponding closely to a working circuit.

Figure 8 shows an example of the posterior distributions inferred over possible faults by each architecture. For this purpose, a component is considered faulty when its value is outside of a 0.3% tolerance of its nominal value. The architectures with attention
manage to most closely fit the ground truth posterior.

4.4 Analysis

Fig. 9 shows the loss of each network throughout training. In every case, the feedforward network with attention performs at least as well as the LSTM-based architecture without attention. In particular, the attention model achieves a significantly better final loss for the plane gene expression model. The plot for the magnitude model with 50 nuisance variables, in which attention also gives an improved final loss, is in the appendix. When only 20 nuisance variables are used, the architecture with attention trains faster but to a similar final loss. We also observe that, in our experiments, using an LSTM and attention in conjunction never provides a significant improvement over using attention alone, while being more computationally costly.

Table 1 shows the time taken to run each architecture. Magnitudes 20 and 50 have 22 and 52 latent variables respectively, the plant gene simulator has 67, and the circuit simulator typically encounters 43. Since each variable is proposed sequentially, inference takes time proportional to the number of latent variables. The computational cost of the attention mechanism is similar to that of the LSTM. Also, although the cost of calculating attention weights, and thus the runtime of the attention mechanism, theoretically scales as the square of the trace length while the LSTM’s runtime scales linearly, their runtimes scale similarly in these experiments.

5 DISCUSSION AND CONCLUSION

We have demonstrated that the standard LSTM core used in IC can fail to capture long-range dependencies between latent variables. To address this, we have proposed an attention mechanism which attends to the most salient previously sampled variables in an execution trace. We show that this architecture can speed-up training and sometimes improve the quality of the learned proposal distributions (measured by the KL divergence loss), while we never observe it harming them. These advantages come at negligible computational cost. We believe this makes the attention-based architecture a sensible default choice for new inference problems. Future work could consider extending the usage of such an attention mechanism to also attend to observed variables. The inference compilation framework is only applicable to models with a fixed number of observations, but such an attention mechanism may allow this requirement to be relaxed.

REFERENCES


APPENDIX

Magnitude of Random Vector

Psuedocode

Program 1: Generative model for the magnitude of a random vector with $M$ nuisance random variables.

```python
def magnitude(obs, M):
    x = sample(Normal(0, 10))
    for _ in range(M):
        # nuisance variables to extend trace
        _ = sample(Normal(0, 10))
    y = sample(Normal(0, 10))
    observe(obs**2, Likelihood=Normal(x**2 + y**2, 0.1))
    return x, y
```

Additional Training Plot

Figure 10: Loss curve for various inference networks for the "Magnitude of random variable" model with 50 nuisance variables.

Attention Weights

Figure 11: Attention weights used on each previously sampled variable when creating a proposal distribution for $y$ in a version of the magnitude model with 10 nuisance variables. Each color represents one of the four queries. The weights are averaged over 100 traces. Queries 1 and 4 attend solely to $x$, explaining how the attention mechanism enables the inference network to capture the long-term dependency, and ignore the nuisance variables.
Figure 12: Attention weights used by an FF w/ ATT inference network on the plant gene expression model. The cells in each row $i$ correspond to the weight given to previously sampled variable when variable $i$ is being sampled. The node numbers correspond to (Opgen-Rhein and Strimmer, 2007).

Electronic Circuit Fault Diagnosis

Program 2: Generative model for the Butterworth filter.

class Butterworth(Model):

    @staticmethod
    def sample_component(name, mean, std=None, p_broken=0.02):
        if std is None:
            std = 0.001 * mean
            broken = pyprob.sample(
                dist.Categorical(
                    torch.tensor([1-p_broken, p_broken]))).item()
        if broken:
            r = pyprob.sample(
                dist.Uniform(torch.tensor([0.]),
                torch.tensor([2.])).item())
            val = r *torch.tensor([mean])
        else:
            r = pyprob.sample(}
dist.Normal(torch.tensor(0),
torch.tensor(1))).item()
val = mean + r*std
return max(val, 1e-16)

@staticmethod
def sample_error(name, p=0.005):
    return bool(pyprob.sample(
        dist.Categorical(
            torch.tensor([1-p, p]))).item())

def forward(self):
    cir = Circuit('Butterworth 1kHz band-pass filter')
    R1 = self.sample_component('R1', mean=50.)
    R1_open = self.sample_error('R1open')
    L1 = self.sample_component('L1', mean=0.245894)
    L1_open = self.sample_error('L1open')
    C1 = self.sample_component('C1', mean=1.03013e-07)
    L2 = self.sample_component('L2', mean=9.83652e-05)
    L2_open = self.sample_error('L2open')
    C2 = self.sample_component('C2', mean=0.000257513)
    C1_open = self.sample_error('C1open')
    if self.sample_error('C1short'):
        cir.add_resistor('Rshort2', 'n3', 'n4', 0.001)
    if self.sample_error('C2short'):
        cir.add_resistor('Rshort2', 'n4', cir.gnd, 0.001)
    C2_open = self.sample_error('C2open')
    if self.sample_error('C3short'):
        cir.add_resistor('Rshort3', 'n5', 'n6', 0.001)
    if self.sample_error('C5open'):
        cir.add_resistor('Rshort5', 'n7', 'n8', 0.001)
    L3 = self.sample_component('L3', mean=0.795775)
    L3_open = self.sample_error('L3open')
    C3 = self.sample_component('C3', mean=3.1831e-08)
    if self.sample_error('C3short'):
        cir.add_resistor('Rshort3', 'n5', 'n6', 0.001)
    C5_open = self.sample_error('C5open')
    L4 = self.sample_component('L4', mean=9.83652e-05)
    L4_open = self.sample_error('L4open')
    C4 = self.sample_component('C4', mean=0.000257513)
    if self.sample_error('C4'):
        cir.add_resistor('Rshort4', 'n6', cir.gnd, 0.001)
    L5 = self.sample_component('L5', mean=0.245894)
    R2_open = self.sample_error('R2open')
    if not Vin_broken:
        cir.add_vsource('V1', 'n1', cir.gnd, dc_value=0., ac_value=1.)
    if not R1_open:
        cir.add_resistor('R1', 'n1', 'n2', R1)
    if not L1_open:
        cir.add_inductor('L1', 'n2', 'n3', L1)
    if not C1_open:
        cir.add_capacitor('C1', 'n3', 'n4', C1)
    if not L2_open:
        cir.add_inductor('L2', 'n4', cir.gnd, L2)
    if not C2_open:
        cir.add_capacitor('C2', 'n4', cir.gnd, C2)
if not L3.open:
    cir.add_inductor('L3', 'n4', 'n5', L3)
if not C3.open:
    cir.add_capacitor('C3', 'n5', 'n6', C3)
if not L4.open:
    cir.add_inductor('L4', 'n6', cir.gnd, L4)
if not C4.open:
    cir.add_capacitor('C4', 'n6', cir.gnd, C4)
if not C5.open:
    cir.add_capacitor('C5', 'n7', 'n8', C5)
if not L5.open:
    cir.add_inductor('L5', 'n6', 'n7', L5)
if not R2.open:
    cir.add_resistor('R2', 'n8', cir.gnd, R2)
else:
    cir.add_resistor('R2', 'n8', cir.gnd, R2*1000)

# analysis
ac1 = new_ac(.97e3, 1.03e3, 40, x0=None)
res = run(cir, ac1)['ac']
vouts = res['Vn8']
rs = abs(vouts)
thetas = np.angle(vouts)

# observations
pyprob.observe(dist.Normal(torch.tensor(rs), torch.tensor(0.03)),
               name='|Vout|')
pyprob.observe(dist.Normal(torch.tensor(thetas), torch.tensor(0.05)),
               name='theta out')